

# TUSB542 USB Type-C™ 5Gbps リドライバ 2 : 1 マルチプレクサ

## 1 特長

- USB Type-C™ ポート用に USB 3.1 Gen-1 5Gbps Super Speed (SS) の 2:1 マルチプレクサを実現
- USB Type-C ケーブルとコネクタの仕様をサポート
- 超低消費電力アーキテクチャ:
  - アクティブ: 100mA
  - U2/U3: 1.3mA
  - 接続なし: 300µA
- 最大 9dB のイコライゼーション、ディエンファシス、最大 6dB の出力スイングを選択可能
- 終端内蔵
- RX 検出機能
- パワー マネージメント用の信号監視
- ホスト側やデバイス側の要件なし – USB-C DFP、UFP、DRP の各ポートをサポート
- 単一電源電圧: 1.8V ± 10%
- -40°C ~ 85°C の産業用温度範囲

## 2 アプリケーション

- USB 3.1 Gen 1 SS アプリケーション:
  - 電話
  - タブレット、ファブレットおよびノートブック PC
  - ドッキング・ステーション

## 3 概要

TUSB542 は、USB-C と呼ばれるデュアル チャネル USB 3.1 Gen1 (5Gbps) で、USB Type-C コネクタを備えたシステムをサポートするリドライバです。このデバイスには、シグナル コンディショニングに加えて、USB Type-C フリップ可能コネクタの USB SS 信号を切り替える機能があります。TUSB542 は、外部の構成チャネル ロジック コントローラにより SEL ピンで制御でき、信号を適切に多重化できます。

TUSB542 はレシーバのイコライゼーションとトランスミッタディエンファシスを内蔵し、送信および受信の両方のデータパスで信号の整合性を維持します。レシーバのイコライゼーションには複数のゲイン設定があり、挿入損失やシンボル間干渉によるチャネルの劣化を克服できます。ダウンストリーム伝送ラインの損失を補償するため、出力ドライバはディエンファシス構成をサポートしています。さらに、自動的な LFPS ディエンファシス制御により、完全な準拠が可能になります。

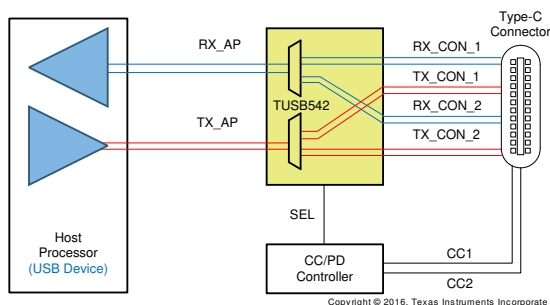
TUSB542 は超低電力アーキテクチャにより 1.8V 電源で動作し、低消費電力を実現します。リドライバは低消費電力モードをサポートしているため、アイドル時の消費電力をさらに減らすことができます。

USB Type-C リドライバは、小型の超薄型パッケージで供給されているため、多くのポータブル アプリケーションに最適です。

### パッケージ情報

部品番号	パッケージ (1)	パッケージ サイズ (2)
TUSB542	RWQ (X2QFN, 18)	2.4mm×2mm

- (1) 詳細については、[セクション 10](#) を参照してください。
- (2) パッケージ サイズ (長さ×幅) は公称値であり、該当する場合はピンも含まれます。



概略回路図



サンプル・アプリケーション



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## 4 Pin Configuration and Functions

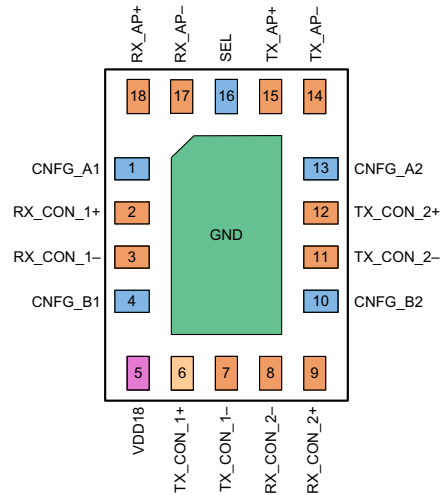


図 4-1. RWQ Package, 18-Pin X2QFN (Top View)

表 4-1. Pin Functions

PIN		TYPE	DESCRIPTION
NAME	NO.		
VDD18	5	P	1.8V Power Supply
GND	PAD	G	Reference Ground Thermal Pad. Must connect to GND on the board.
SEL	16	Input	2:1 SS MUX control. See Table 1 for signal path settings.210kΩ internal pullup resistor. H: AP SS signals are connected to Type-C position 1 signals. L: AP SS signals are connected to Type-C position 2 signals
CNFG_A1	1	Tri-level Input	Tri-level configuration input pin A1 (for Ch 1): sets channel 1 (AP to redriver) EQ, DE and OS configurations. Pin has integrated pull-up and pull-down resistors of 105kΩ. Refer to 表 6-2 for configuration settings.
CNFG_B1	4	Tri-level Input	Tri-level configuration input pin B1 (for Ch 1): sets channel 1 (AP to redriver) EQ, DE and OS configurations. Pin has integrated pull-up and pull-down resistors of 105kΩ. Refer to 表 6-2 for configuration settings.
CNFG_A2	13	Tri-level Input	Tri-level configuration input pin A2 (for Ch 2): sets channel 2 (redriver to device) EQ, DE and OS configurations. Pin has integrated pull-up and pull-down resistors of 10 5kΩ. Refer to 表 6-2 for configuration settings.
CNFG_B2	10	Tri-level Input	Tri-level configuration input pin B2 (for Ch 2): sets channel 2 (redriver to device) EQ, DE and OS configurations. Pin has integrated pull-up and pull-down resistors of 105kΩ. Refer to 表 6-2 for configuration settings.
RX_AP+	18	Diff output	Differential output to Application Processor (AP), 5 Gbps SS positive signal
RX_AP-	17	Diff output	Differential output to AP, 5Gbps SS negative signal
TX_AP+	15	Diff input	Differential input from AP, 5Gbps SS positive signal
TX_AP-	14	Diff input	Differential input from AP, 5Gbps SS negative signal
Rx_Con_1+	2	Diff input	Differential input from Type-C Connector, Position 1, SS positive signal
Rx_Con_1-	3	Diff input	Differential input from Type-C Connector, Position 1, SS negative signal
Tx_Con_1+	6	Diff output	Differential output to Type-C Connector, Position 1, SS positive signal
Tx_Con_1-	7	Diff output	Differential output to Type-C Connector, Position 1, SS negative signal
Rx_Con_2-	8	Diff input	Differential input from Type-C Connector, Position 2, SS negative signal
Rx_Con_2+	9	Diff input	Differential input from Type-C Connector, Position 2, SS positive signal
Tx_Con_2+	12	Diff output	Differential output to Type-C Connector, Position 2, SS positive signal
Tx_Con_2-	11	Diff output	Differential output to Type-C Connector, Position 2, SS negative signal

## 5 Specifications

### 5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

	MIN	MAX	UNIT	
Supply voltage range, $V_{CC}$	-0.3	2.3	V	
Voltage range at any input or output terminal	Differential I/O	-0.3	1.5	V
	CMOS Inputs	-0.3	2.3	V
Junction temperature, $T_J$	-40	105	°C	
Storage temperature, $T_{stg}$	-65	150	°C	

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### 5.2 ESD Ratings

	VALUE	UNIT
$V_{(ESD)}$ Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>	±2000
	Charged-device model (CDM), per JEDEC specification JESD22-C101 <sup>(2)</sup>	±500

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.  
 (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

### 5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

	MIN	NOM	MAX	UNIT
$V_{CC}$ Main power supply	1.62	1.8	1.98	V
$T_A$ Operating free-air temperature	-40		85	°C
$C_{(AC)}$ AC coupling capacitor required for TX pins	75		200	nF
$V_{(PSN)}$ AC coupling capacitor required for TX pins			100	mV
$t_{(VCC\_RAMP)}$ $V_{CC}$ supply ramp requirement	0.2		40	ms
$R_{(pullup-down)}$ Pull-up/down resistor to control CNF pins			2.2	kΩ

### 5.4 Thermal Information

THERMAL METRIC <sup>(1)</sup>	TUSB542		UNIT
	X2QFN (RWQ)		
	18 PINS		
$R_{\theta JA}$ Junction-to-ambient thermal resistance	83.4		°C/W
$R_{\theta JC(top)}$ Junction-to-case (top) thermal resistance	52		°C/W
$R_{\theta JB}$ Junction-to-board thermal resistance	49.1		°C/W
$\psi_{JT}$ Junction-to-top characterization parameter	0.6		°C/W
$\psi_{JB}$ Junction-to-board characterization parameter	49.1		°C/W
$R_{\theta JC(bot)}$ Junction-to-case (bottom) thermal resistance	n/a		°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

## 5.5 Electrical Characteristics, Power Supply Currents

over operating free-air temperature range (unless otherwise noted)

PARAMETER	MIN	TYP	MAX	UNIT
ICC(ACTIVE) (Average active current; link in U0 with SuperSpeed data transmission; OS = 0.9V; DE = 0dB)		100	130	mA
ICC(U2/U3) (Average current in U2/U3)		1.3		mA
ICC(NC) (Average current with no connection No SuperSpeed device is connected to TXP/TXN)		0.3		mA

## 5.6 Electrical Characteristics, DC

over operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>TRI-STATE CMOS INPUTS (CNFG_A1, CNFG_B1, CNFG_A2 and CNFG_B2)</b>					
V <sub>IH</sub>	High-level input voltage	V <sub>CC</sub> × 0.75			V
V <sub>IM</sub>	Mid-level input voltage		V <sub>CC</sub> / 2		V
V <sub>IL</sub>	Mid-level input voltage			V <sub>CC</sub> × 0.25	V
V <sub>F</sub>	Floating voltage	V <sub>IN</sub> = High impedance	V <sub>CC</sub> / 2		V
R <sub>(PU)</sub>	Internal pull-up resistance		105		kΩ
R <sub>(PD)</sub>	Internal pull-down resistance		105		kΩ
I <sub>IH</sub>	High-level input current	V <sub>IN</sub> = 1.98V		26	μA
I <sub>IL</sub>	Low-level input current	V <sub>IN</sub> = GND	-26		μA
I <sub>Ikg</sub>	External leakage current (from application board + Application Processor pin high impedance) tolerance	V <sub>IN</sub> = GND or V <sub>IN</sub> = 1.98V	-1	1	μA
<b>CMOS INPUT – SEL</b>					
V <sub>IH</sub>	High-level input voltage	V <sub>CC</sub> × 0.7			V
V <sub>IL</sub>	Mid-level input voltage			V <sub>CC</sub> × 0.3	V
I <sub>IH</sub>	High-level input current	V <sub>IN</sub> = 1.98V		5	μA
I <sub>IL</sub>	Low-level input current	V <sub>IN</sub> = GND	-16		μA

## 5.7 Electrical Characteristics, Dynamic

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>Differential Receiver</b>						
$V_{(RX-DC-CM)}$	RX DC common mode voltage		0		2	V
$R_{(RX-CM-DC)}$	Receiver DC common mode impedance	Measured at connector. Present when SuperSpeed USB device detected on TX pins.	18		30	$\Omega$
$R_{(RX-DIFF-DC)}$	Receiver DC differential impedance	Measured at connector. Present when SuperSpeed USB device detected on TX pins.	72		120	$\Omega$
$Z_{(RX-HIGH-IMP-DC-POS)}$	DC input CM input impedance when termination is disabled.	Measured at connector. Present when no SuperSpeed USB device detected on TX pins or while $V_{CC}$ is ramping.	25			k $\Omega$
$V_{(RX-LFPS-DET-DIFF-P-P)}$	LFPS Detect threshold. Below min is noise.	Measured at connector. Below min is squelched.	0.1		0.3	V
$V_{(RX-CM-AC-P)}$	Peak RX AC common mode voltage	Measured at package pin.			150	mV
$C_{(RX-PARASITIC)}$	Rx Input capacitance for return loss	At package pin to AC GND.			1.1	pF
<b>Differential Transmitter</b>						
$V_{(TX-DIFF-PP)}$	Differential peak-to-peak TX voltage swing	OS Low, 0dB DE		0.9		V
		OS High, 0dB DE		1.1		V
$V_{(TX-DIFF-PP-LFPS)}$	LFPS differential voltage swing	OS Low, High	0.8		1.2	V
$V_{(TX-DE-RATIO)}$	Transmitter de-emphasis	Low		0		dB
		Mid		3.5		dB
		High		6		dB
$V_{(TX-RCV-DETECT)}$	The amount of voltage change allowed during Receiver Detection.				0.6	V
$V_{(TX-DC-CM)}$	TX DC common mode voltage	The instantaneous allowed DC common-mode voltage at connector side of AC coupling capacitor.	0		2	V
$V_{(TX-IDLE-DIFF-AC-PP)}$	AC Electrical Idle differential peak-to-peak output voltage	At package pin.	0		10	mV
$V_{(TX-IDLE-DIFF-DC)}$	DC Electrical Idle differential output voltage	At package pin. After low pass filter to remove AC component.	0		10	nV
$V_{(TX-CM-DC-ACTIVE-IDLE-DELTA)}$	Absolute DC common mode voltage between U1 and U0.	At package pin.			0.2	V
$I_{(TX-SHORT)}$	TX short-circuit current limit				60	mA
$R_{(TX-DC)}$	TX DC common mode impedance	At package pins	18		30	$\Omega$
$R_{(TX-DIFF-DC)}$	TX DC differential impedance		72		120	$\Omega$
$C_{(TX-PARASTIC)}$	TX input capacitance for return loss	At package pins to AC GND			1.25	pF
$T_{(jitter)}$	Total Residual Jitter (peak to peak)			12		ps

## 5.8 Electrical Characteristics, AC

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Xtalk	Differential Cross talk between TX and RX Signal Pairs	at 2.5 GHz, TX to RX		-45		dB

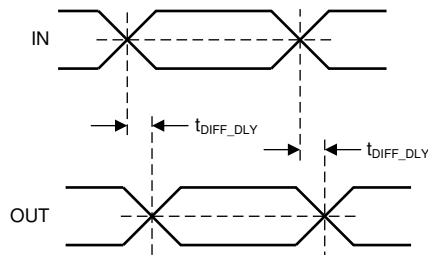
## 5.9 Timing Requirements

			MIN	NOM	MAX	UNIT
$t_{IDLEEntry}$	Delay from U0 to electrical idle.	See 5-2		6		ns
$t_{IDLEExit_U1}$	U1 exit time: break in electrical idle to the transmission of LFPS	See 5-2		6		ns
$t_{IDLEExit_U2U3}$	U2/U3 exit time: break in electrical idle to transmission of LFPS	From the time when the far end terminations detected for both ports		1		$\mu$ s
$t_{IDLEExit_DISC}$	U2/U3 exit time: break in electrical idle to transmission of LFPS	From the time when the far end terminations detected for both ports		2		$\mu$ s
$t_{DIFF-DLY}$	Differential propagation delay.	See 5-1		225		ps
$t_{PWRUPACTIVE}$	Time when $V_{CC}$ reach 80% to device active				30	ms

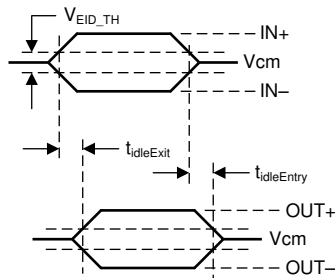
## 5.10 Switching Characteristics

over operating free-air temperature range (unless otherwise noted)

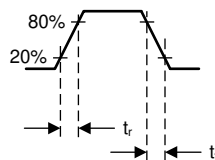
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{TX-RISE-FALL}$	Transmitter rise/fall time (see Figure 3)		80		ps
$t_{RF-MISMATCH}$	Transmitter rise/fall mismatch			2.3	ps



5-1. Propagation Delay Timing



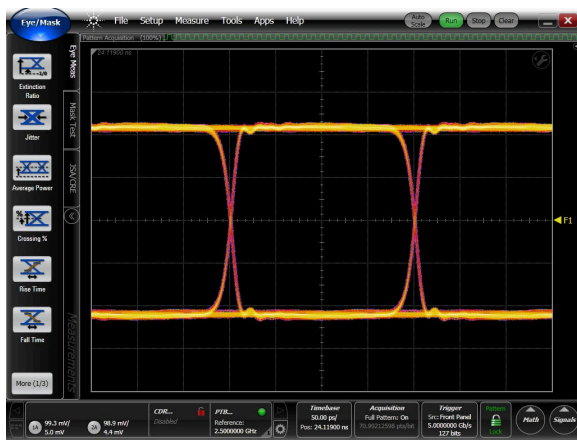
5-2. Electrical Idle Mode Exit and Entry Delay Timing




5-3. Output Rise and Fall Times

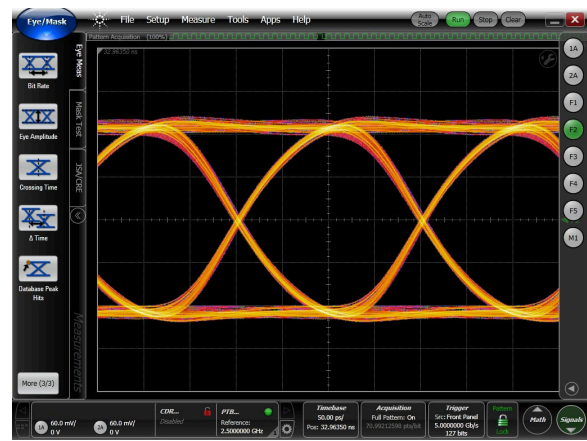
## 5.11 Typical Characteristics


### 5.11.1 1-Inch Pre Channel

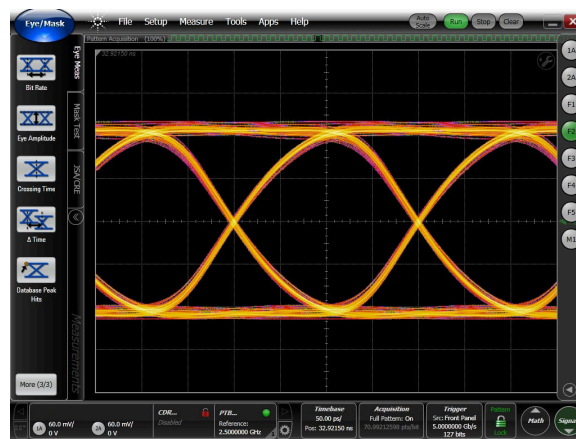


880 mV 5Gbps


 5-4. Input Signal: 1-Inch Input Trace



 5-5. Output Signal: 12-Inches Output Trace

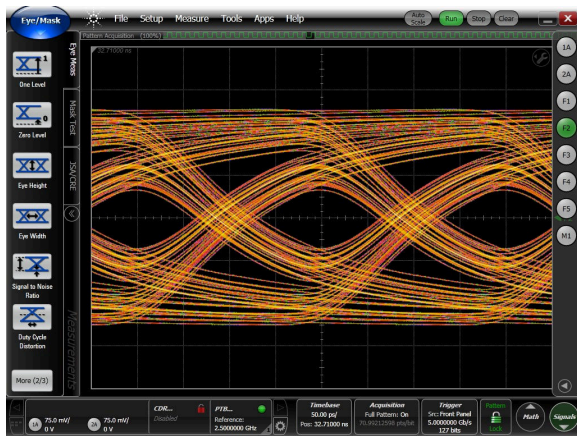


A.

 5-6. Output Signal: 16-Inches Output Trace

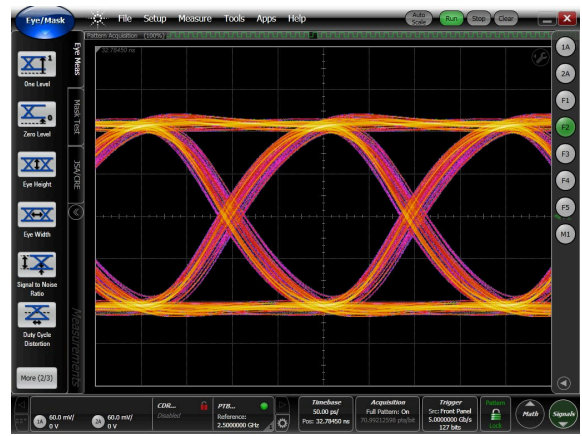


### 5.11.2 24-Inch Pre Channel

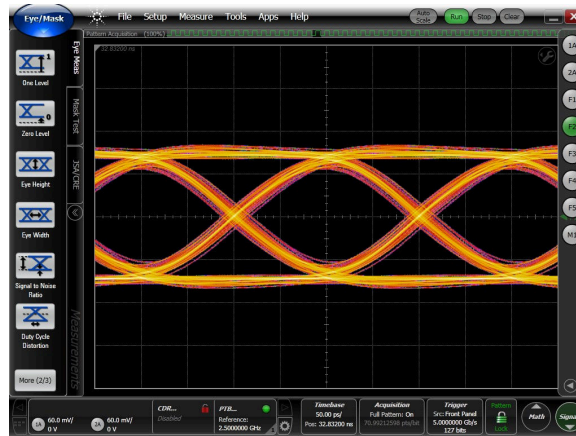


880 mV 5Gbps

**5-7. Input Signal: 24-Inch Input Trace**

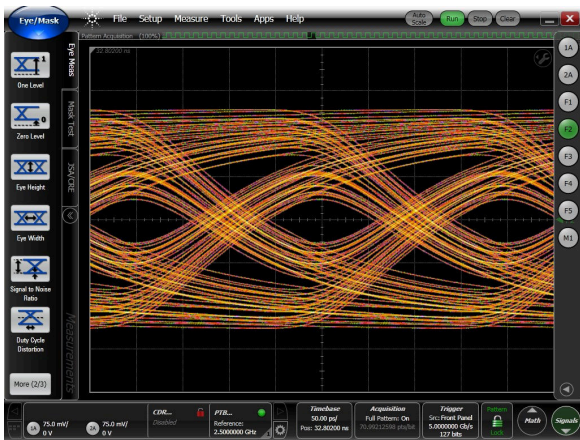


**5-8. Output Signal: 12-Inches Output Trace**

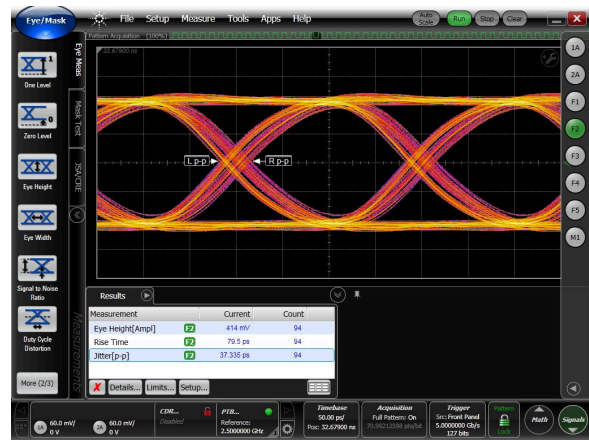


**5-9. Output Signal: 24-Inches Output Trace**

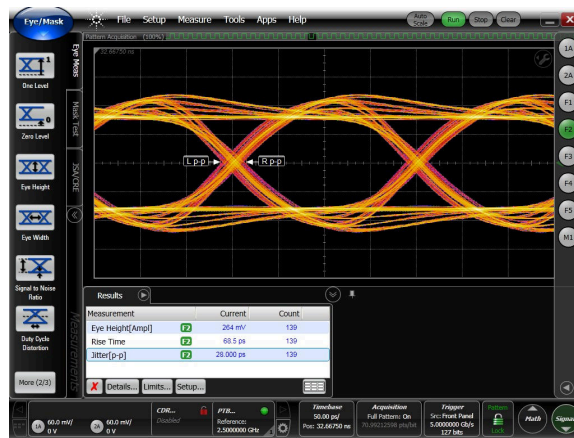
### 5.11.3 32-Inch Pre Channel



880 mV 5Gbps  
**5-10. Input Signal: 32-Inch Input Trace**



**5-11. Output Signal: 12-Inches Output Trace**



**5-12. Output Signal: 24-Inches Output Trace**

## 6 Detailed Description

### 6.1 Overview

TUSB542 is an active re-driver for USB 3.1 Gen1 applications; it supports Type-C applications, as well as switching between two Hosts and one device (or vice versa). The device is a dual channel USB 3.1 Gen1 (5Gbps) re-driver supporting systems with USB Type-C connectors. The TUSB542 can be controlled through the SEL, and is best controlled using an external Configuration Channel Logic or Power Delivery Controller to properly mux the signals in Type-C applications.

When 5Gbps Super Speed USB signals travel across a PCB or cable, signal integrity degrades due to loss and inter-symbol interference. The TUSB542 recovers incoming data by applying equalization that compensates for channel loss, and drives out signals with a high differential voltage. This extends the possible channel length, and enables systems to pass USB 3.1 compliance.

The TUSB542 advanced state machine makes it transparent to hosts and devices. After power up, the TUSB542 periodically performs receiver detection on the TX pair. If it detects a SS USB receiver, the RX termination is enabled, and the TUSB542 is ready to re-drive.

The TUSB542 operates over the industrial temperature range of  $-40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$  in the 2 mm x 2.4 mm X2QFN package. The device ultra-low power architecture operates at a 1.8V power supply. The automatic LFPS DeEmphasis control further enables the system to be USB 3.0 compliant. An advanced state machine inside the device monitors the USB SS traffic to perform enhanced power management to operate in no-connect, U2, U3 and active modes.

The USB Type-C connector is designed to allow insertion either upside-up or downside-up. The TUSB542 supports this feature by routing the AP signals to one of two output channels. The SEL input control defines the way that the AP side signals are routed on the re-driver device side. 表 6-1 lists the active MUX configurations based on the SEL input.

表 6-1. USB SS MUX Control

SEL	Tx_Con_1	Rx_Con_1	Tx_Con_2	Rx_Con_2
H	TX_AP	RX_AP	GND	GND <sup>(1)</sup>
L	GND	GND <sup>(1)</sup>	TX_AP	RX_AP

(1) Terminated through 50 K (minimum) resistors

The TUSB542 has flexible configurations to optimize the device using GPIO control pins. 図 6-1 shows a typical signal chain for mobile applications. Channel 1 is between Application Processor (AP) and TUSB542, Channel 2 is between the TUSB542 re-driver and the downstream device. The CNFG\_A1 and CNFG\_B1 pins provide signal integrity configuration settings for channel 1, while CNFG\_A2 and CNFG\_B2 pins control the operation of Channel 2 as listed in 表 6-2.

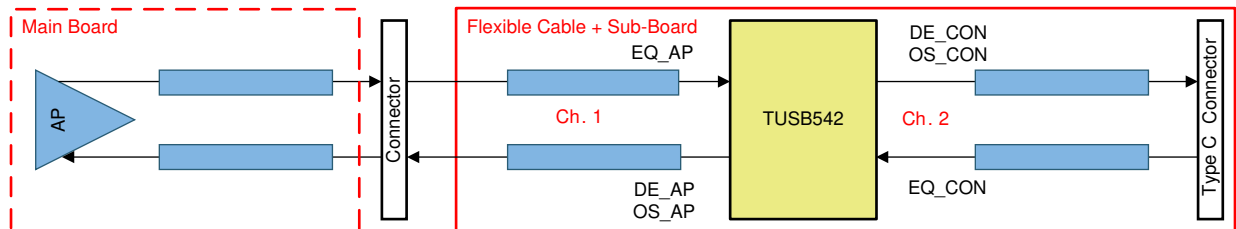


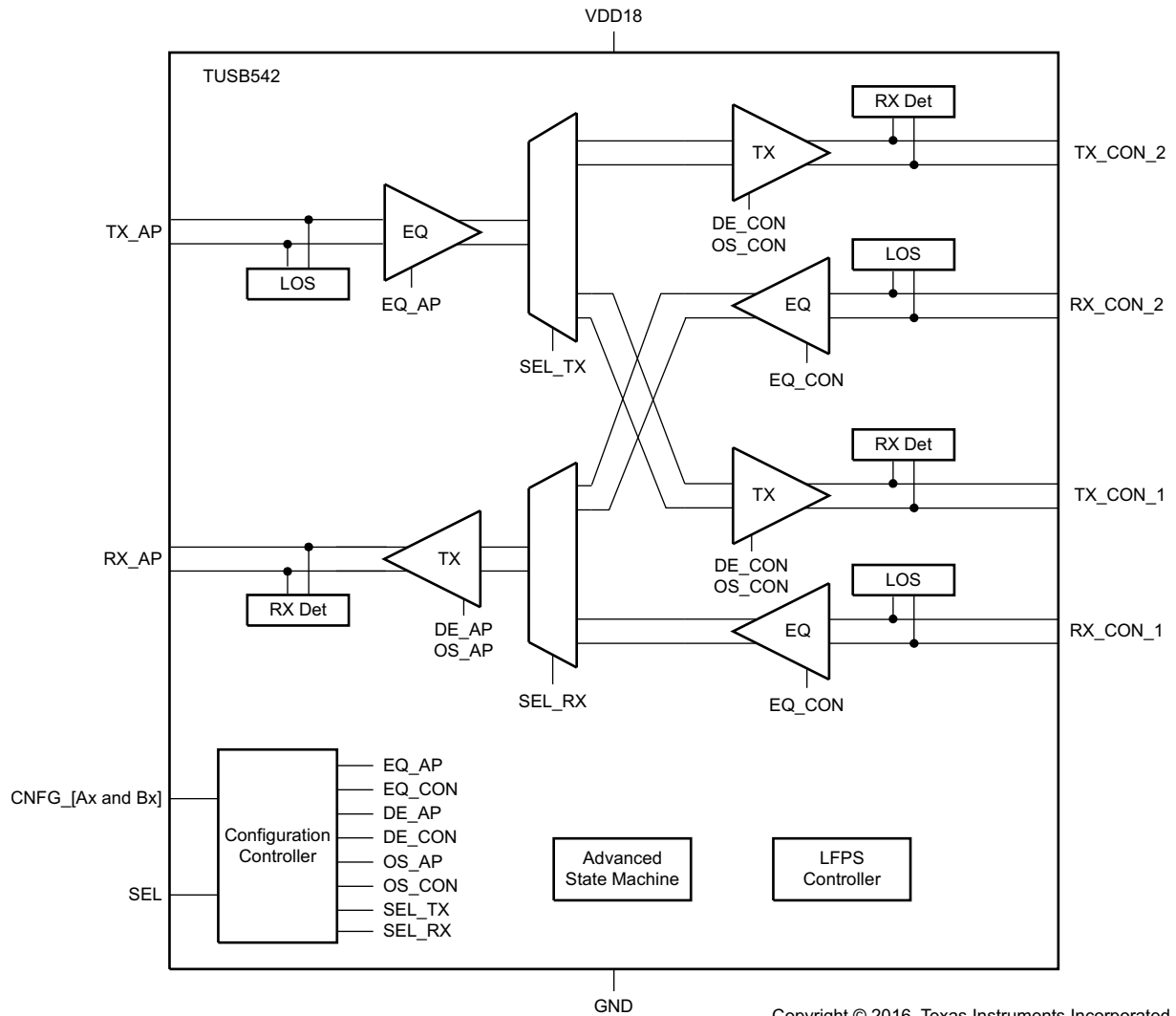
図 6-1. Typical Channels

The receiver (RX) of the device provides the flexibility of 0, 3, 6 and 9dB of equalization, while the transmitter (TX) provides the options of 0, 3.5 or 6dB de-emphasis. The transmitter also supports output swing settings of 900 mV and 1.1V.

表 6-2. Device Signal Conditioning Configuration Settings for TUSB542

Ch1 (AP-Redriver)		DE_AP (dB)	OS_AP (V)	EQ_AP (dB)	Ch2 (Redriver-Conn)		DE_Conn (dB)	OS_Conn (V)	EQ_Conn (dB)
CNFG_A1	CNFG_B1				CNFG_A2	CNFG_B2			
Low	Low	3.5	1.1	3	Low	Low	6	1.1	0
	Float	3.5	0.9	3		Float	3.5	1.1	0
	High	0	1.1	3		High	3.5	0.9	0
Float	Low	0	0.9	3	Float	Low	6	0.9	0
	Float	3.5	1.1	0		Float	3.5	1.1	6
	High	.35	0.9	0		High	3.5	0.9	6
High	Low	0	1.1	0	High	Low	6	1.1	6
	Float	0	0.9	0		Float	6	0.9	6
	High	6	1.1	6		High	6	1.1	9

## 6.2 Functional Block Diagram



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## 6.3 Feature Description

### 6.3.1 Receiver Equalization

The purpose of receiver equalization is to compensate for channel insertion loss and inter-symbol interference in the system before the input of the TUSB542 receiver. The receiver overcomes these losses by providing gain to the high frequency components of the signals with respect to the low frequency components. The proper gain setting should be selected to match the channel insertion loss before the receiver input of the TUSB542.

### 6.3.2 De-Emphasis Control and Output Swing

The output differential drivers of the TUSB542 provide selectable de-emphasis and output swing to achieve USB3.1 compliance, these options are configurable by means of 3-state control pins, and its available settings are listed on the 表 6-2. The level of de-emphasis required in the system depends on the channel length after the output of the re-driver. 図 6-2 shows transmit bits with de-emphasis.

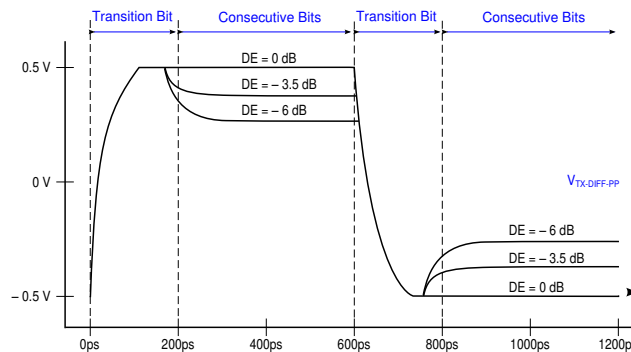


図 6-2. Transmitter Differential Voltage in Presence of De-Emphasis

### 6.3.3 Automatic LFPS Detection

The TUSB542 features an intelligent low frequency periodic signaling (LFPS) controller. The controller senses the low frequency signals and automatically disables the driver de-emphasis, for full USB3.1 compliance.

### 6.3.4 Automatic Power Management

The TUSB542 deploys RX detect, LFPS signal detection and signal monitoring to implement an automatic power management scheme to provide active, U2/U3 and disconnect modes. The automatic power management is driven by an advanced state machine, which is implemented to manage the device such that the re-driver operates smoothly in the links.

## 6.4 Device Functional Modes

### 6.4.1 Disconnect Mode

The Disconnect mode is the lowest power state of the TUSB542. In this state, the TUSB542 periodically checks for far-end receiver termination on both TX. Upon detection of the far-end receiver's termination on both ports, the TUSB542 will transition to U0 mode.

### 6.4.2 U Modes

#### 6.4.2.1 U0 Mode

The U0 mode is the highest power state of the TUSB542. Anytime super-speed traffic is being received, the TUSB542 remains in this mode.

#### 6.4.2.2 U2/U3 Mode

Next to the disconnect mode, the U2/U3 mode is next lowest power state. While in this mode, the TUSB542 periodically performs far-end receiver detection.

## 7 Application and Implementation


### 注

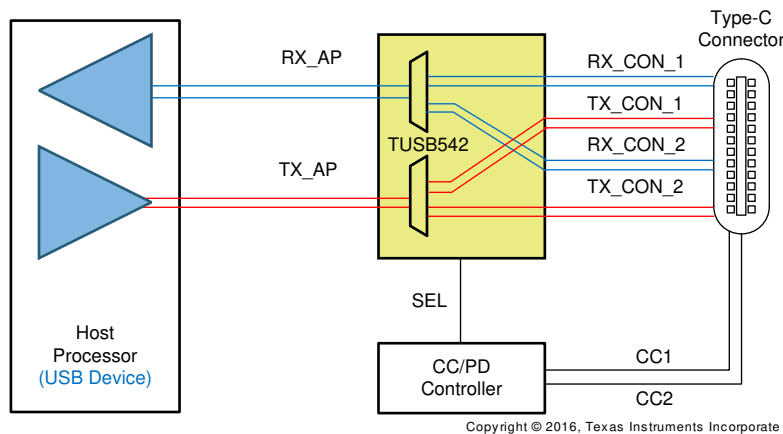
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### 7.1 Application Information

TUSB542 is a USB 3.1 G1 5Gbps super speed 1:2 or 2:1 redriver de-multiplexer/multiplexer for RX and TX differential pairs. The device is host/device side agnostic and can be used for host or device switching.

### 7.2 Typical Applications, USB Type-C Port SS MUX

TUSB542 is optimized for USB Type-C port. The device provide multiplexing to select appropriate super speed RX and TX signal pairs resulting from Type-C plug orientation flipping. A companion USB PD or CC controller provides the MUX selection. The device can be used part of UFP, DFP or DRP Type-C port.  7-1 shows typical Type-C applications.



 7-1. USB Type-C Host (Device) Application

### 7.2.1 Design Requirements


For this design example, use the parameters provided in [Design Parameters](#).

The configured value depends on the physical channel (PCB layout) Equalization 0, 3, 6, 9dB (5Gbps) The configured value depends on the physical channel (PCB layout) de-emphasis 0, -3.5, -6dB The configured value depends on the physical channel (PCB layout) Differential impedance 72 - 120 Ω.

**表 7-1. Design Parameters**

PARAMETER	VALUE	COMMENT
VDD18	1.8V	
AC Coupling Capacitors for SS signals	100 nF	75-200 nF range allowed. TUSB542 biases both input and output common mode voltage, hence ac-coupling caps as required on both sides. Note: TX pairs need to be biased at the connector.
Pull-up/down resistor to control CNF pins	4.7kΩ	
Input voltage range	100 mV to 1200 mV	
Output voltage range	900 mV to 1100 mV	

### 7.2.2 Detailed Design Procedure

 [7-2](#) shows an example implementation of an USB Type-C DRP port using TUSB542. Texas Instruments TUSB322 is shown here as channel configuration (CC) controller. Note: connections for CNFG pins of TUSB542 is an example only. The connection of the CNFG pins is application dependent; refer to [表 6-2](#), where the user can find the available settings.

It is recommended to run an overall system signal integrity analysis, to estimate the channel loss and configure the re-driver. It is also recommended to have pull-up and pull-down option on the configuration pins for debug and testing purposes.

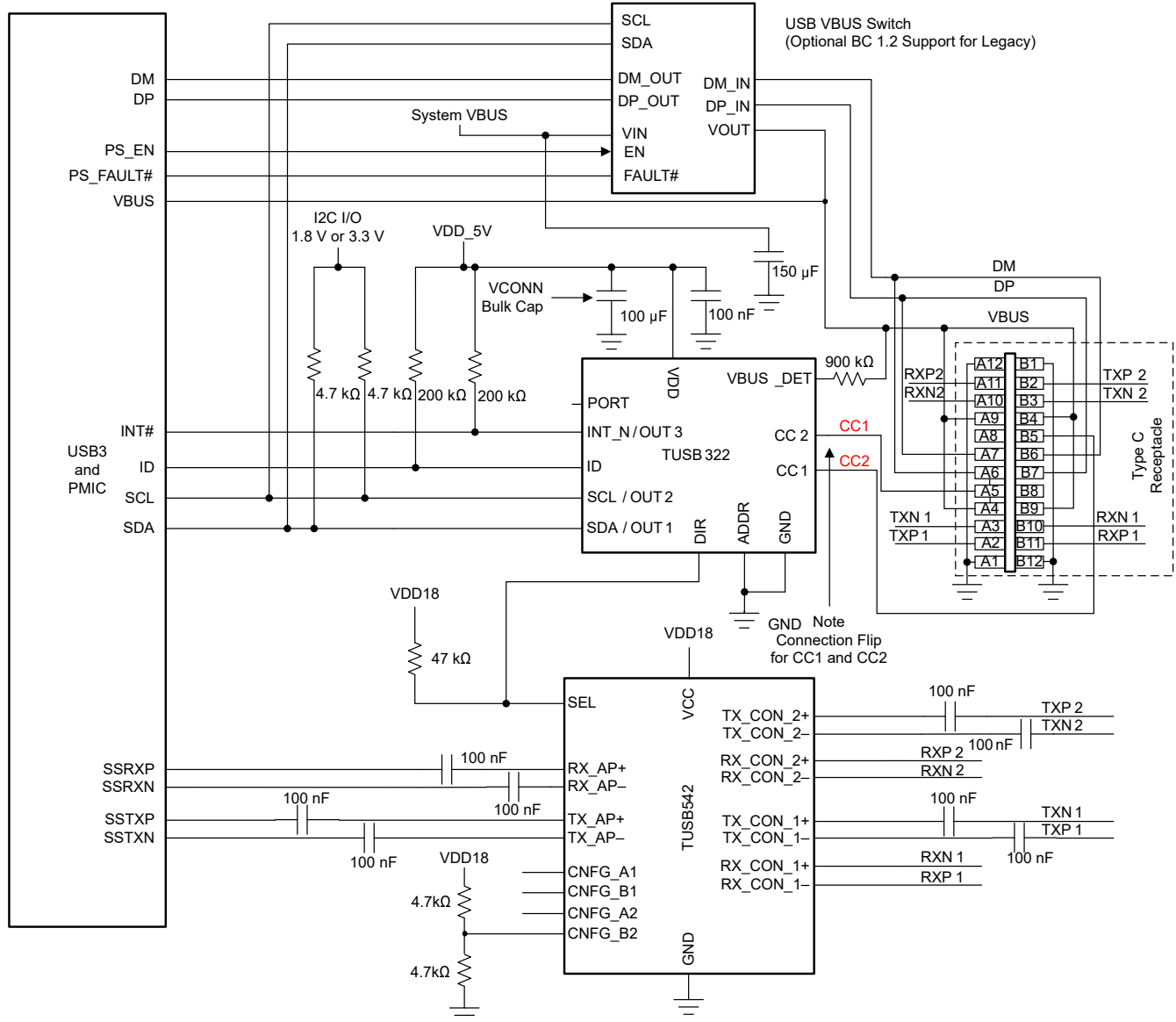
The signal integrity analysis must determine the following:

- Equalization (EQ) setting
- De-emphasis (DE) setting
- Output swing amplitude (OS) setting

The equalization must be set based on the insertion loss in the pre-channel (channel before the TUSB542 device). The input voltage to the device is able to have a large range because of the receiver sensitivity and the available EQ settings.

The de-emphasis setting must be set based on the length and characteristics of the post channel (channel after the TUSB542 device).





7-2. USB-C DRP Implementation Using TUSB542 and TUSB322/TUSB321



### 7.2.3 Application Curves

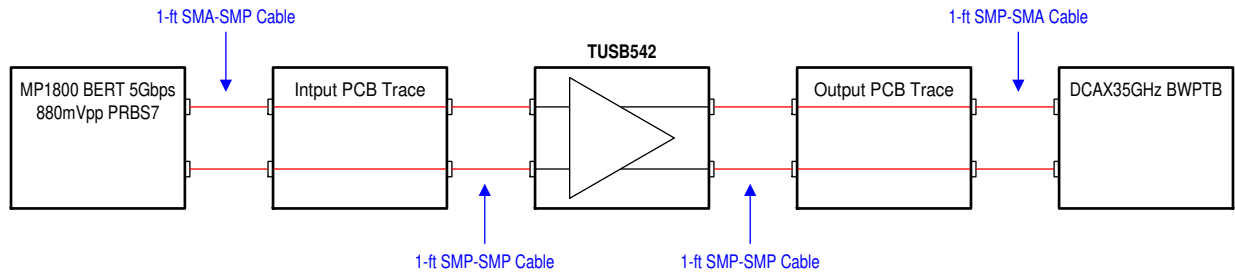


图 7-3. Measurement Setup

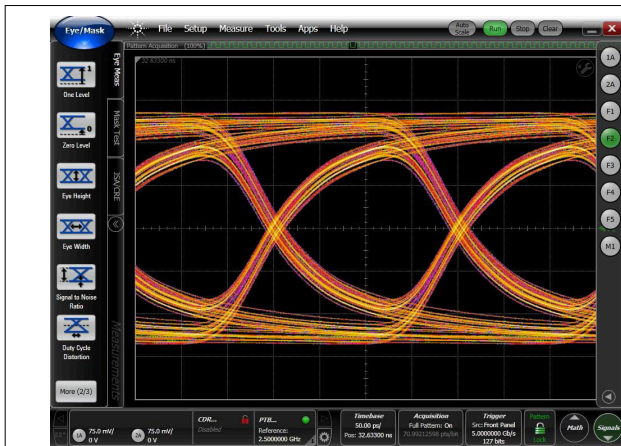


图 7-4. Input Signal: 12 Inch Input Trace (Eye Diagram at the Re-driver input)

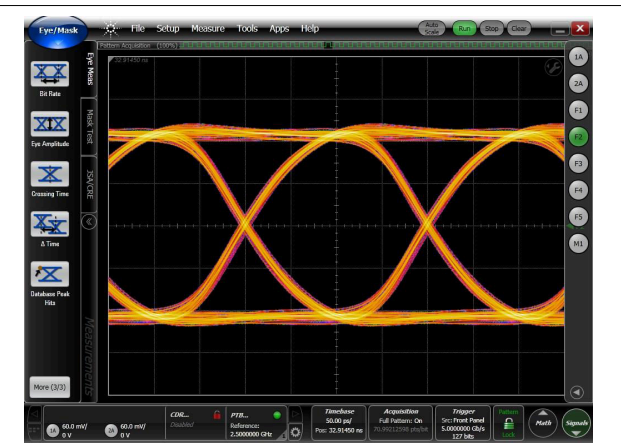


图 7-5. Output Signal: 12 Inch Output Trace (Eye Diagram at the DCAX)

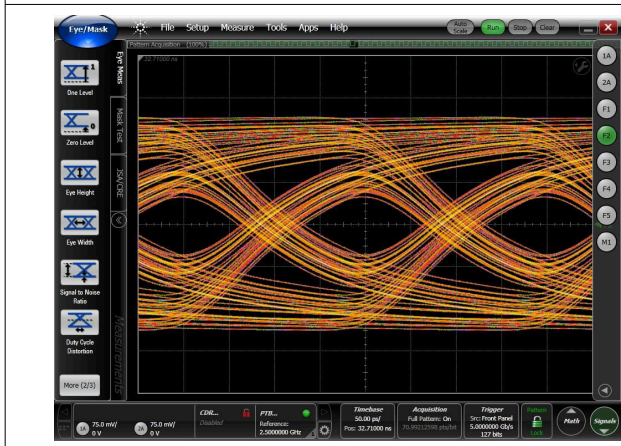


图 7-6. Input Signal: 24 Inch Input Trace (Eye Diagram at the Re-driver input)

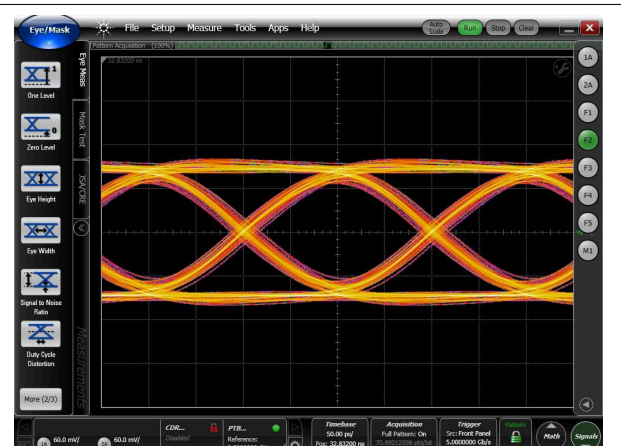
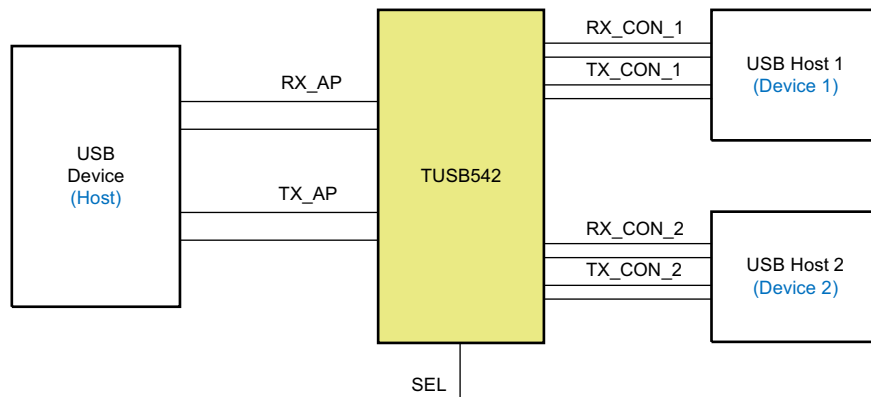


图 7-7. Output Signal: 24 Inch Output Trace (Eye Diagram at the DCAX)

## 7.3 Typical Application: Switching USB SS Host or Device Ports

TUSB542, being USB SS mux/demux, can be used for host or device switching. [Figure 7-8](#) illustrates how the device can be used:



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**Figure 7-8. Muxing Two Host (Device) Port**

### 7.3.1 Design Requirements

For this design example, use the design parameters shown in [Design Parameters](#).

The configured value depends on the physical channel (PCB layout) Equalization 0, 3, 6, 9dB (5Gbps) The configured value depends on the physical channel (PCB layout) de-emphasis 0, -3.5, -6dB The configured value depends on the physical channel (PCB layout) Differential impedance 72 - 120  $\Omega$

**Table 7-2. Design Parameters**

PARAMETER	VALUE	COMMENT
VDD18	1.8V	
AC Coupling Capacitors for SS signals	100 nF	75-200 nF range allowed. TUSB542 biases both input and output common mode voltage, hence ac-coupling caps as required on both sides. Note: TX pairs need to be biased at the connector.
Pull-up/down resistor to control CNF pins	4.7k $\Omega$	
Input voltage range	100 mV to 1200 mV	
Output voltage range	900 mV to 1100 mV	

### 7.3.2 Detailed Design Procedure

[Figure 7-2](#) shows an example implementation of an USB Type-C DRP port using TUSB542. Texas Instruments TUSB322 is shown here as channel configuration (CC) controller. Note: connections for CNFG pins of TUSB542 is an example only. The connection of the CNFG pins is application dependent; refer to the [Table 6-2](#), where the user can find the available settings.

It is recommended to run an overall system signal integrity analysis, to estimate the channel loss and configure the re-driver. It is also recommended to have pull-up and pull-down option on the configuration pins for debug and testing purposes.

The signal integrity analysis must determine the following:

- Equalization (EQ) setting
- De-emphasis (DE) setting
- Output swing amplitude (OS) setting

The equalization must be set based on the insertion loss in the pre-channel (channel before the TUSB542 device). The input voltage to the device is able to have a large range because of the receiver sensitivity and the available EQ settings.

The de-emphasis setting must be set based on the length and characteristics of the post channel (channel after the TUSB542 device).

The output swing setting can also be configured based on the amplitude needed to pass the compliance test. This setting is also based on the length of interconnect or cable the TUSB542 is driving.

Refer to the [表 6-2](#) for a detailed description on how to configure the CONFIG\_A1/A2 and CONFIG\_B1/A2 terminals, to achieve the desired EQ, OS, and DE settings.

### 7.3.3 Application Curves

For this design example, use the application curves shown in [セクション 7.2.3](#).

## 7.4 Power Supply Recommendations

TUSB542 has internal power on reset circuit to provide clean reset for state machine provided supply ramp and level recommendations are met.

## 7.5 Layout

### 7.5.1 Layout Guidelines

- RXP/N and TXP/N pairs should be routed with controlled 90-Ω differential impedance ( $\pm 15\%$ ).
- Keep away from other high speed signals.
- Intra-pair routing should be kept to within 2 mils.
- Length matching should be near the location of mismatch.
- Each pair should be separated at least by 3 times the signal trace width.
- The use of bends in differential traces should be kept to a minimum. When bends are used, the number of left and right bends should be as equal as possible and the angle of the bend should be  $\geq 135$  degrees. This will minimize any length mismatch causes by the bends and therefore minimize the impact bends have on EMI.
- Route all differential pairs on the same of layer.
- The number of VIAS should be kept to a minimum. It is recommended to keep the VIAS count to 2 or less.
- Keep traces on layers adjacent to ground plane.
- *Do not* route differential pairs over any plane split.
- Adding test points will cause impedance discontinuity, and therefore; negatively impacts signal performance. If test points are used, they should be placed in series and symmetrically. They must not be placed in a manner that causes a stub on the differential pair.

### 7.5.2 Layout Example

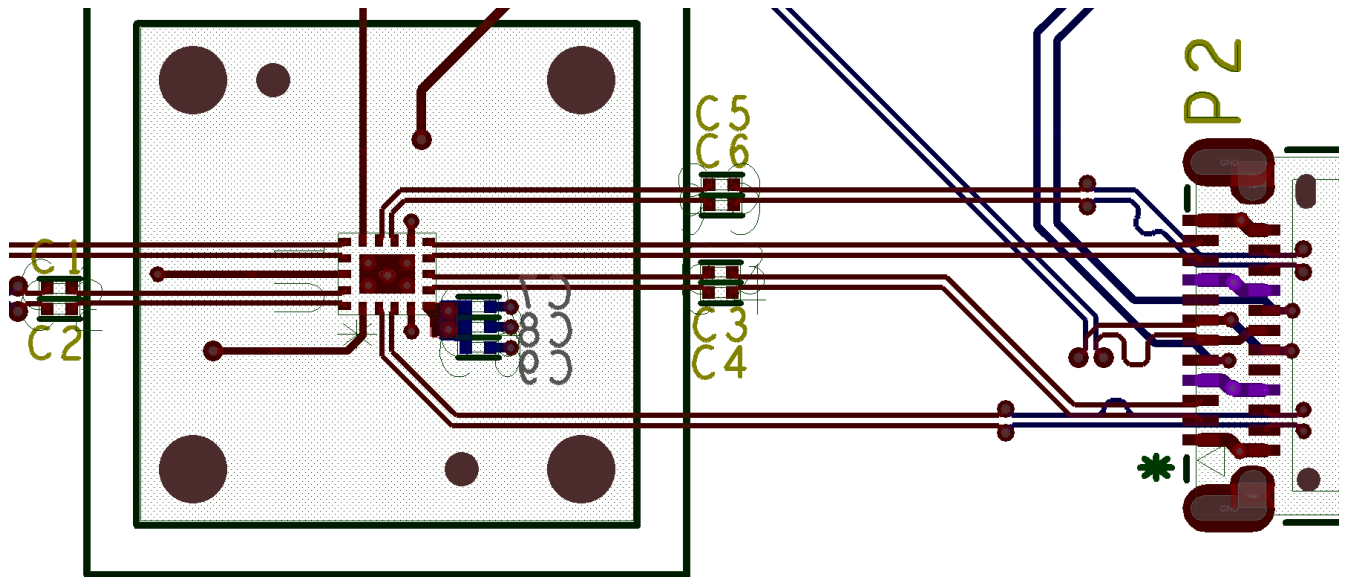


図 7-9. Example Layout

## 8 Device and Documentation Support

### 8.1 ドキュメントの更新通知を受け取る方法

ドキュメントの更新についての通知を受け取るには、[www.tij.co.jp](http://www.tij.co.jp) のデバイス製品フォルダを開いてください。[通知] をクリックして登録すると、変更されたすべての製品情報に関するダイジェストを毎週受け取ることができます。変更の詳細については、改訂されたドキュメントに含まれている改訂履歴をご覧ください。

### 8.2 サポート・リソース

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### 8.5 用語集

[テキサス・インスツルメンツ用語集](#) この用語集には、用語や略語の一覧および定義が記載されています。

## 9 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

Changes from Revision E (April 2017) to Revision F (December 2023)	Page
• Changed Junction temperature MIN value to -40 from -65 in the <i>Absolute Maximum Ratings</i> table.....	4
• Changed Junction temperature MAX value to 105 from 150 in the <i>Absolute Maximum Ratings</i> table.....	4
• Changed Storage temperature MAX value to 150 from 105 in the <i>Absolute Maximum Ratings</i> table.....	4
Changes from Revision D (March 2017) to Revision E (April 2017)	Page
• 「特長」を以下のように変更:「イコライゼーション、ディエンファシス、出力スイングを選択可能」から「最大 9dB のイコライゼーション、ディエンファシス、最大 6dB の出力スイングを選択可能」.....	1
• 「特長」の自動 LFPS ディエンファシス制御による USB 3.1 準拠.....	1
• 「特長」を以下のように変更:「USB DFP、UFP、DRP ポートをサポート可能」から「USB-C DFP、UFP、DRP ポートをサポート」.....	1
• アプリケーションを以下のように変更:「USB Type-C SS アプリケーション」から「USB 3.1 Gen 1 SS アプリケーション」.....	1
• 「概略回路図」を変更 .....	1
• Changed the first five paragraphs of the <i>Overview</i> section.....	11
• Changed <a href="#">図 7-1</a> .....	14
• Changed the <i>Design Requirements</i> and the <i>Detailed Design Procedure</i> section of <i>Typical Applications, USB Type-C Port SS MUX</i> section.....	15

- Changed the *Design Requirements* and the *Detailed Design Procedure* section of *Typical Application: Switching USB SS Host or Device Ports* ..... 18

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**Changes from Revision C (August 2016) to Revision D (March 2017) Page**

- Added a MIN value of –65 to the Storage temperature in the *Absolute Maximum Ratings* table..... 4

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**Changes from Revision B (January 2016) to Revision C (August 2016) Page**

- Changed Pin 15 To: TX\_AP+ and Pin 14 To: TX\_AP- in the RWQ Package image..... 3

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**Changes from Revision A (January 2016) to Revision B (January 2016) Page**

- Changed the RX\_AP+ (pin 18) and RX\_AP- (pin 17) I/O Type and Description to Diff output .....3
- Changed the TX\_AP+ (pin 15) and RX\_AP- (pin 14) I/O Type and Description to Diff input ..... 3

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**Changes from Revision \* (December 2015) to Revision A (January 2016) Page**

- 「概略回路図」の TX\_AP ピンと RX\_AP ピンを変更 ..... 1
- Changed the RX\_AP+, RX\_AP- and TX\_AP+, TX\_PA- pins in the RWQ Package image..... 3
- Changed pin RX\_AP+ number From: 15 To: 18.....3
- Changed pin RX\_AP- number From: 14 To: 17.....3
- Changed pin TX\_AP+ number From: 18 To: 15..... 3
- Changed pin TX\_AP- number From: 17 To: 14..... 3
- Changed 表 6-1 ..... 11
- Changed 図 6-1 ..... 11
- Changed the セクション 6.2 ..... 12
- Changed location of pins SSTXP, SSTXN and SSRXP, SSRXN in 図 7-2 ..... 15

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## 10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



**PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TUSB542RWQR	ACTIVE	X2QFN	RWQ	18	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	54	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSELETE:** TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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**TAPE AND REEL INFORMATION**

**QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TUSB542RWQR	X2QFN	RWQ	18	3000	179.0	8.4	2.25	2.65	0.53	4.0	8.0	Q1



**TAPE AND REEL BOX DIMENSIONS**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TUSB542RWQR	X2QFN	RWQ	18	3000	213.0	191.0	35.0

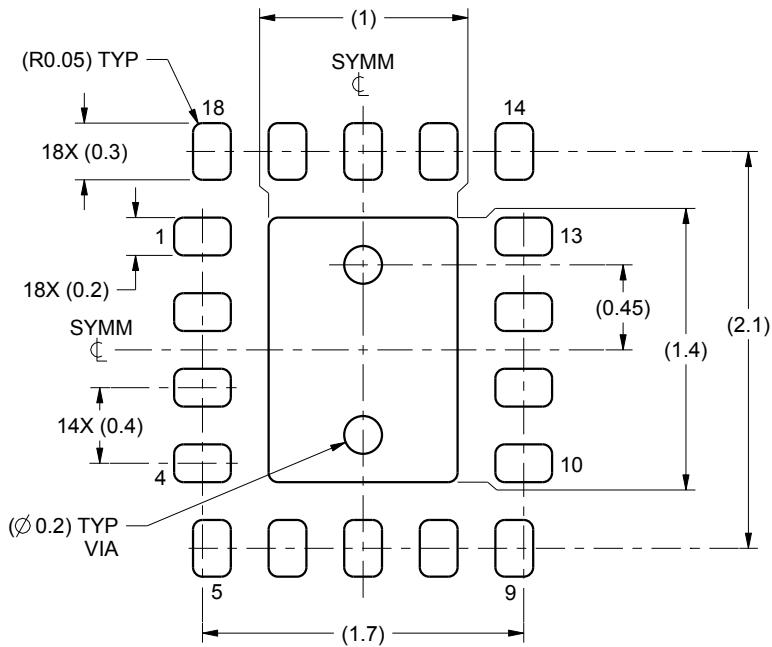


# EXAMPLE BOARD LAYOUT

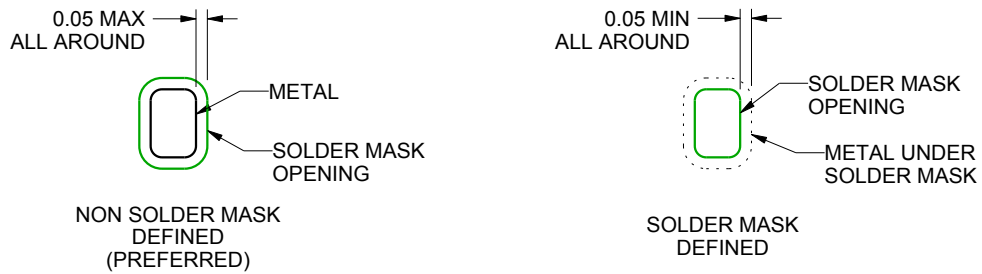
RWQ0018A

X2QFN - 0.4 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



LAND PATTERN EXAMPLE  
SCALE:25X



SOLDER MASK DETAILS

4221962/B 06/2016

NOTES: (continued)

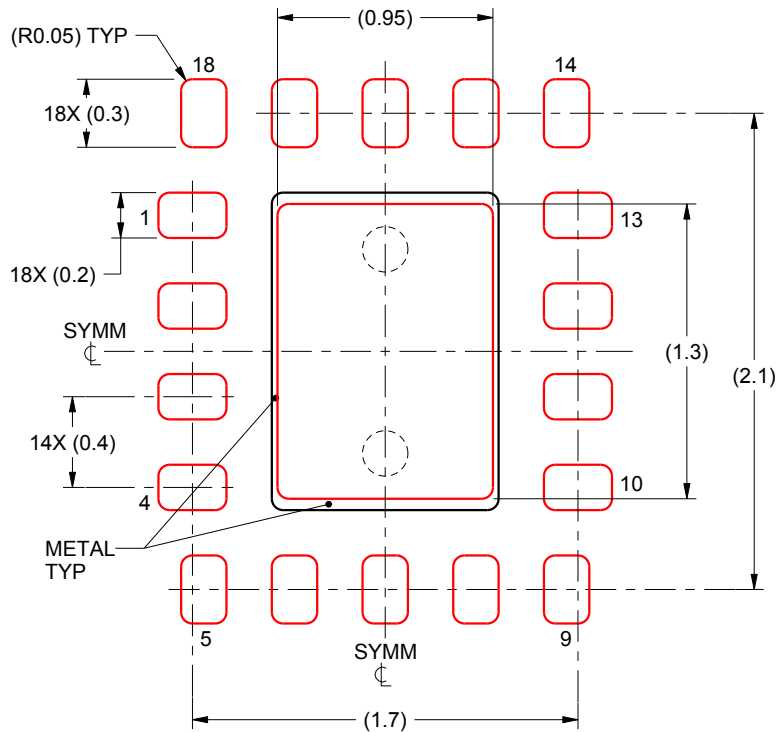
4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 ([www.ti.com/lit/sluea271](http://www.ti.com/lit/sluea271)).

# EXAMPLE STENCIL DESIGN

RWQ0018A

X2QFN - 0.4 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



**SOLDER PASTE EXAMPLE**  
BASED ON 0.1 mm THICK STENCIL

EXPOSED PAD  
88% PRINTED SOLDER COVERAGE BY AREA  
SCALE:30X

4221962/B 06/2016

NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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